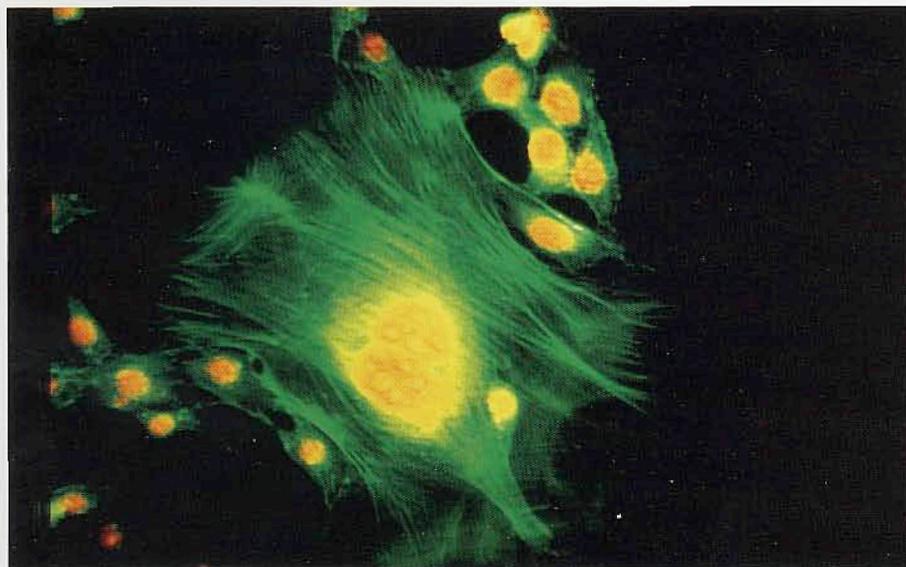


MICROSCOPY TODAY

APRIL 1995

ISSUE #95-3



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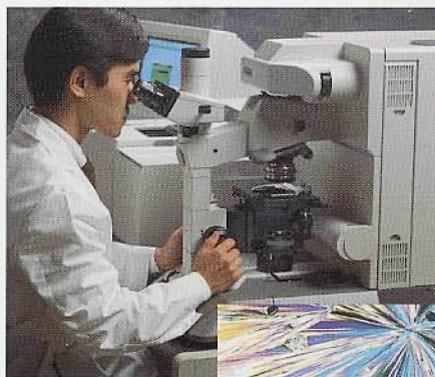
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Whether you are analyzing the layers in a multi-layer film, searching for the contaminant that made your part fail, identifying the origin of trace evidence or researching new adhesive bonds, Nicolet and Spectra-Tech have an infrared microscope to fit your needs *and* your budget – from the basic Laboratory IR-Plan® microscope to the high performance Nic-Plan™ research microscope.

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Circle Reader Inquiry #17